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5 CONTROL OF SCANNER BEAM MISPLACEMENT

Sommario/riassunto

Written by an award-winning leader in the field, this is a thoroughly integrated overview of the many facets and disciplines of optical scanning. Of particular utility to both practitioner and student are such features as: An overview of the technology and unifying principles, including active and passive scanning, optical transfer, and system architectureIn-depth chapters on scanning theory and processes, scanned resolution, scanner devices and techniques, and the control of scanner beam misplacemenA comprehensive review of the government-sponsored research of agile